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Kind regards,

Team Nexperia



# PMCXB1000UE

30 V, complementary N/P-channel Trench MOSFET

27 June 2016

Product data sheet

## 1. General description

Complementary N/P-channel enhancement mode Field-Effect Transistor (FET) in a leadless ultra small DFN1010B-6 (SOT1216) Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

## 2. Features and benefits

- Trench MOSFET technology
- Very low threshold voltage for portable applications:  $V_{GS(th)} = 0.7\text{ V}$
- Leadless ultra small and ultra thin SMD plastic package:  $1.1 \times 1.0 \times 0.37\text{ mm}$
- ElectroStatic Discharge (ESD) protection  $> 2\text{ kV HBM}$

## 3. Applications

- Relay driver
- High-speed line driver
- Level shifter
- Power management in battery-driven portables

## 4. Quick reference data

Table 1. Quick reference data

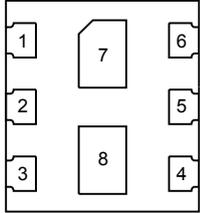
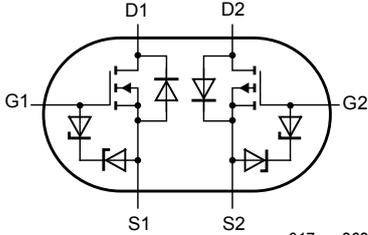
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>TR1 (N-channel), Static characteristics</b>						
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 4.5\text{ V}; I_D = 590\text{ mA}; T_j = 25\text{ °C}$	-	550	670	m $\Omega$
<b>TR2 (P-channel), Static characteristics</b>						
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = -4.5\text{ V}; I_D = -410\text{ mA}; T_j = 25\text{ °C}$	-	1.2	1.4	$\Omega$
<b>TR1 (N-channel)</b>						
$V_{DS}$	drain-source voltage	$T_j = 25\text{ °C}$	-	-	30	V
$I_D$	drain current	$V_{GS} = 4.5\text{ V}; T_{amb} = 25\text{ °C}$	[1]	-	590	mA
<b>TR2 (P-channel)</b>						
$V_{DS}$	drain-source voltage	$T_j = 25\text{ °C}$	-	-	-30	V
$I_D$	drain current	$V_{GS} = -4.5\text{ V}; T_{amb} = 25\text{ °C}$	[1]	-	-410	mA

[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain  $1\text{ cm}^2$ .



### 5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source TR1	 <p>Transparent top view <b>DFN1010B-6 (SOT1216)</b></p>	 <p>017aaa262</p>
2	G1	gate TR1		
3	D2	drain TR2		
4	S2	source TR2		
5	G2	gate TR2		
6	D1	drain TR1		
7	D1	drain TR1		
8	D2	drain TR2		

### 6. Ordering information

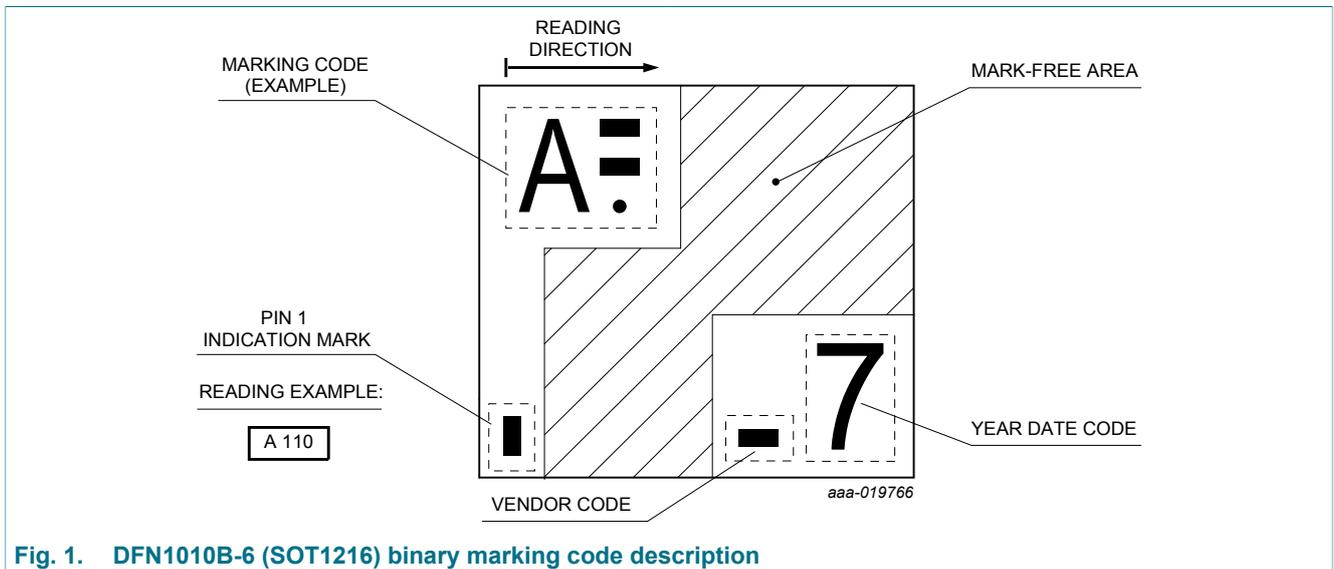
Table 3. Ordering information

Type number	Package		Version
	Name	Description	
PMCXB1000UE	DFN1010B-6	DFN1010B-6: plastic thermal enhanced ultra thin small outline package; no leads; 6 terminals	SOT1216

### 7. Marking

Table 4. Marking codes

Type number	Marking code
PMCXB1000UE	B 101



## 8. Limiting values

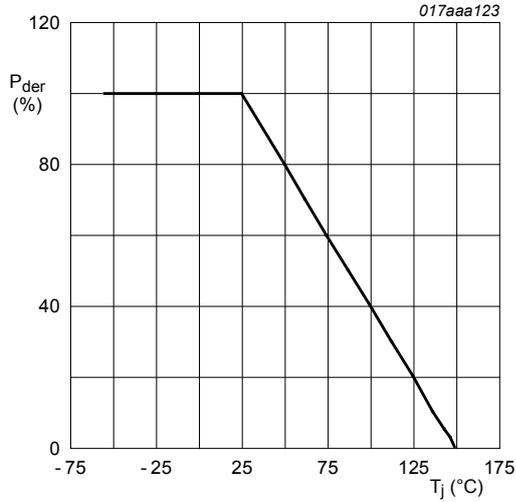
**Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
<b>TR1 (N-channel)</b>						
$V_{DS}$	drain-source voltage	$T_j = 25\text{ °C}$		-	30	V
$V_{GS}$	gate-source voltage			-8	8	V
$I_D$	drain current	$V_{GS} = 4.5\text{ V}; T_{amb} = 25\text{ °C}$	[1]	-	590	mA
		$V_{GS} = 4.5\text{ V}; T_{amb} = 100\text{ °C}$	[1]	-	370	mA
$I_{DM}$	peak drain current	$T_{amb} = 25\text{ °C}; \text{single pulse}; t_p \leq 10\text{ }\mu\text{s}$		-	2.3	A
$P_{tot}$	total power dissipation	$T_{amb} = 25\text{ °C}$	[2]	-	285	mW
			[1]	-	410	mW
		$T_{sp} = 25\text{ °C}$		-	4	W
<b>TR2 (P-channel)</b>						
$V_{DS}$	drain-source voltage	$T_j = 25\text{ °C}$		-	-30	V
$V_{GS}$	gate-source voltage			-8	8	V
$I_D$	drain current	$V_{GS} = -4.5\text{ V}; T_{amb} = 25\text{ °C}$	[1]	-	-410	mA
		$V_{GS} = -4.5\text{ V}; T_{amb} = 100\text{ °C}$	[1]	-	-260	mA
$I_{DM}$	peak drain current	$T_{amb} = 25\text{ °C}; \text{single pulse}; t_p \leq 10\text{ }\mu\text{s}$		-	-1.7	A
$P_{tot}$	total power dissipation	$T_{amb} = 25\text{ °C}$	[2]	-	285	mW
			[1]	-	410	mW
		$T_{sp} = 25\text{ °C}$		-	4	W
<b>Per device</b>						
$T_j$	junction temperature			-55	150	°C
$T_{amb}$	ambient temperature			-55	150	°C
$T_{stg}$	storage temperature			-65	150	°C
<b>TR1 (N-channel), Source-drain diode</b>						
$I_S$	source current	$T_{amb} = 25\text{ °C}$	[1]	-	380	mA
<b>TR2 (P-channel), Source-drain diode</b>						
$I_S$	source current	$T_{amb} = 25\text{ °C}$	[1]	-	-410	mA

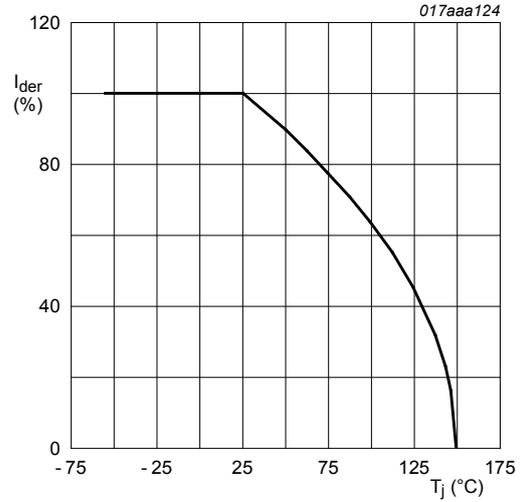
[1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm<sup>2</sup>.

[2] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.



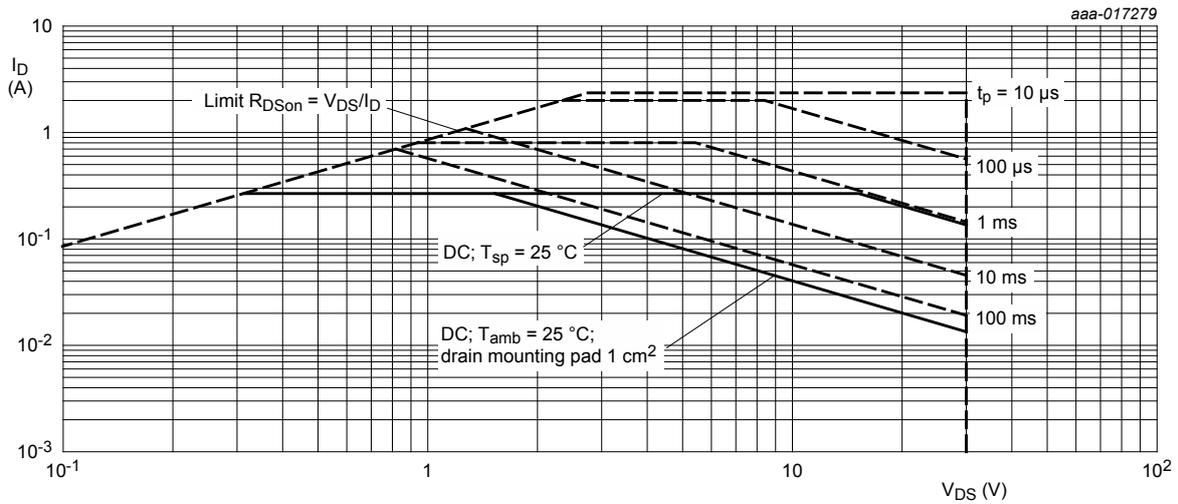
$$P_{der} = \frac{P_{tot}}{P_{tot(25^\circ C)}} \times 100 \%$$

**Fig. 2. MOSFET transistor: Normalized total power dissipation as a function of junction temperature**

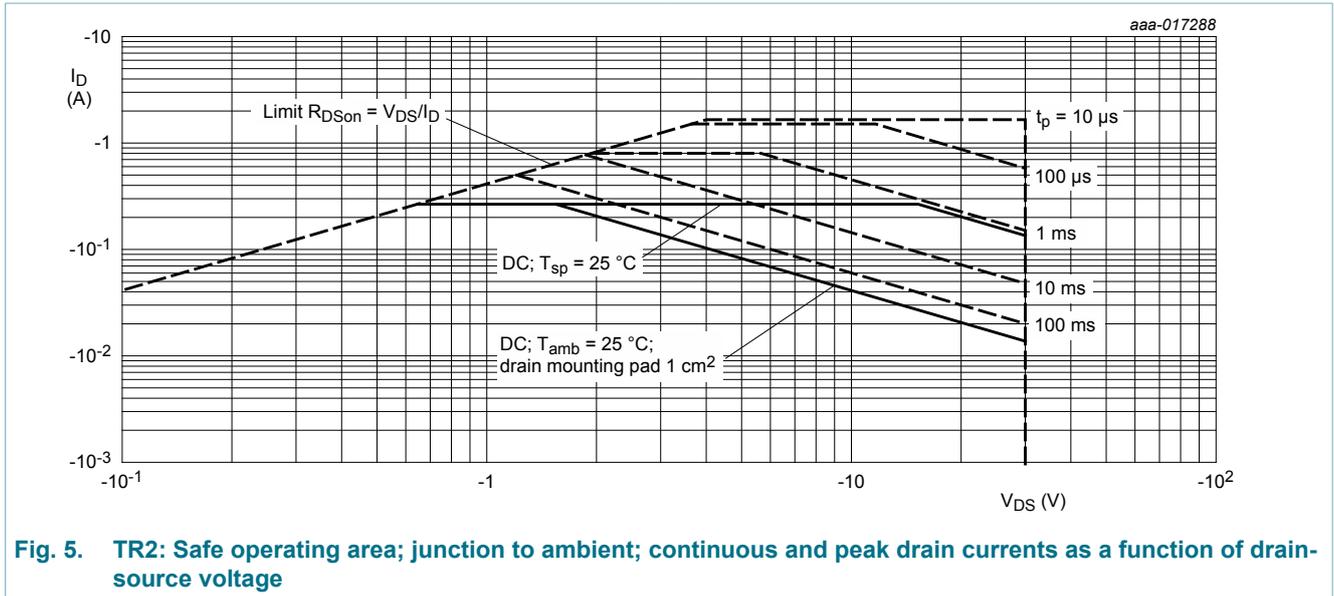


$$I_{der} = \frac{I_D}{I_{D(25^\circ C)}} \times 100 \%$$

**Fig. 3. MOSFET transistor: Normalized continuous drain current as a function of junction temperature**



**Fig. 4. TR1: Safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage**



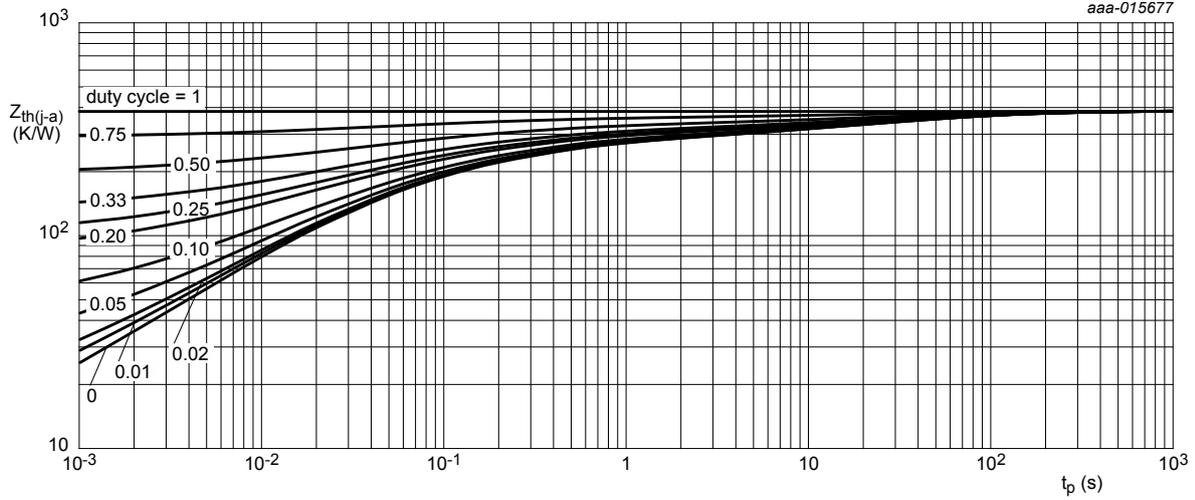
## 9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
<b>TR1 (N-channel)</b>							
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	[1]	-	380	440	K/W
			[2]	-	275	305	K/W
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point			-	27	31	K/W
<b>TR2 (P-channel)</b>							
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	in free air	[1]	-	380	440	K/W
			[2]	-	275	305	K/W
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point			-	27	31	K/W

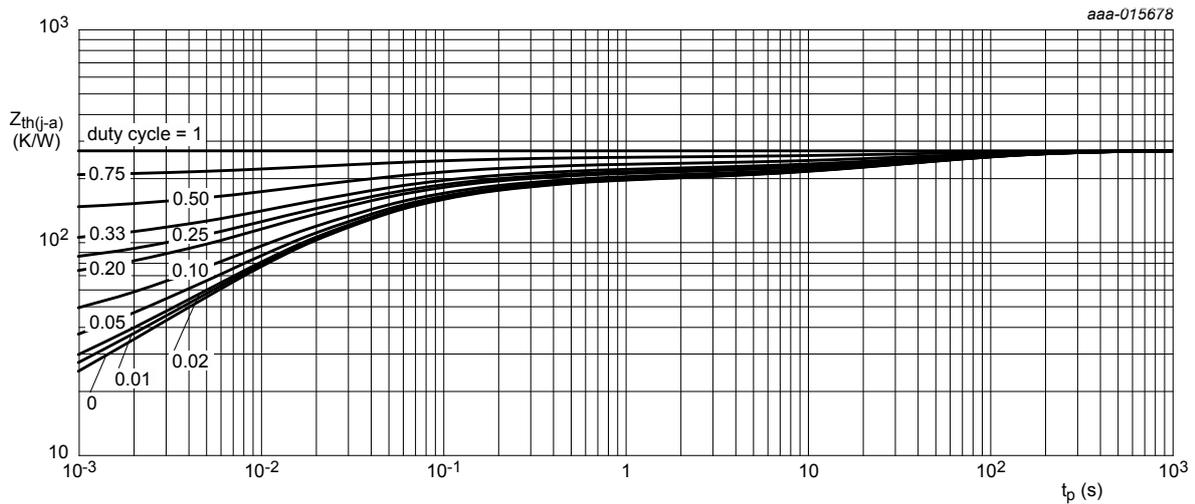
[1] Device mounted on an FR4 PCB, single-sided copper; tin-plated and standard footprint.

[2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for drain 1 cm<sup>2</sup>.



FR4 PCB, standard footprint

Fig. 6. TR1 and TR2: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for drain 1 cm<sup>2</sup>

Fig. 7. TR1 and TR2: Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

## 10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>TR1 (N-channel), Static characteristics</b>						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$	30	-	-	V
$V_{GSth}$	gate-source threshold voltage	$I_D = 250 \mu A; V_{DS}=V_{GS}; T_j = 25 \text{ }^\circ C$	0.45	0.7	0.95	V
$I_{DSS}$	drain leakage current	$V_{DS} = 30 V; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	1	$\mu A$
$I_{GSS}$	gate leakage current	$V_{GS} = 8 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	5	$\mu A$
		$V_{GS} = -8 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	-5	$\mu A$
		$V_{GS} = 4.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	1	$\mu A$
		$V_{GS} = -4.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	-1	$\mu A$
		$V_{GS} = 2.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	100	nA
		$V_{GS} = -2.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	-100	nA
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 4.5 V; I_D = 590 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	550	670	m $\Omega$
		$V_{GS} = 4.5 V; I_D = 590 \text{ mA}; T_j = 150 \text{ }^\circ C$	-	960	1170	m $\Omega$
		$V_{GS} = 2.5 V; I_D = 590 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	660	900	m $\Omega$
		$V_{GS} = 1.8 V; I_D = 80 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	770	1120	m $\Omega$
		$V_{GS} = 1.5 V; I_D = 10 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	890	1500	m $\Omega$
$g_{fs}$	forward transconductance	$V_{DS} = 10 V; I_D = 590 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	600	-	mS
<b>TR2 (P-channel), Static characteristics</b>						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = -250 \mu A; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$	-30	-	-	V
$V_{GSth}$	gate-source threshold voltage	$I_D = -250 \mu A; V_{DS}=V_{GS}; T_j = 25 \text{ }^\circ C$	-0.45	-0.7	-0.95	V
$I_{DSS}$	drain leakage current	$V_{DS} = -30 V; V_{GS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	-1	$\mu A$
$I_{GSS}$	gate leakage current	$V_{GS} = 8 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	5	$\mu A$
		$V_{GS} = -8 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	-5	$\mu A$
		$V_{GS} = 4.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	1	$\mu A$
		$V_{GS} = -4.5 V; T_j = 25 \text{ }^\circ C$	-	-	-1	$\mu A$
		$V_{GS} = 2.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	100	nA
		$V_{GS} = -2.5 V; V_{DS} = 0 V; T_j = 25 \text{ }^\circ C$	-	-	-100	nA
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = -4.5 V; I_D = -410 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	1.2	1.4	$\Omega$
		$V_{GS} = -4.5 V; I_D = -410 \text{ mA}; T_j = 150 \text{ }^\circ C$	-	2	2.4	$\Omega$
		$V_{GS} = -2.5 V; I_D = -320 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	1.7	2.3	$\Omega$
		$V_{GS} = -1.8 V; I_D = -80 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	2.1	3.1	$\Omega$
		$V_{GS} = -1.5 V; I_D = -10 \text{ mA}; T_j = 25 \text{ }^\circ C$	-	3	5.1	$\Omega$

30 V, complementary N/P-channel Trench MOSFET

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$g_{fs}$	forward transconductance	$V_{DS} = -10\text{ V}; I_D = -410\text{ mA}; T_j = 25\text{ }^\circ\text{C}$	-	820	-	mS
<b>TR1 (N-channel), Dynamic characteristics</b>						
$Q_{G(tot)}$	total gate charge	$V_{DS} = 15\text{ V}; I_D = 590\text{ mA}; V_{GS} = 4.5\text{ V}; T_j = 25\text{ }^\circ\text{C}$	-	0.6	1.05	nC
$Q_{GS}$	gate-source charge		-	0.1	-	nC
$Q_{GD}$	gate-drain charge		-	0.1	-	nC
$C_{iss}$	input capacitance	$V_{DS} = 15\text{ V}; f = 1\text{ MHz}; V_{GS} = 0\text{ V}; T_j = 25\text{ }^\circ\text{C}$	-	30.3	-	pF
$C_{oss}$	output capacitance		-	5.8	-	pF
$C_{rss}$	reverse transfer capacitance		-	4.2	-	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = 15\text{ V}; I_D = 590\text{ mA}; V_{GS} = 4.5\text{ V}; R_{G(ext)} = 6\text{ }\Omega; T_j = 25\text{ }^\circ\text{C}$	-	4	-	ns
$t_r$	rise time		-	7	-	ns
$t_{d(off)}$	turn-off delay time		-	12	-	ns
$t_f$	fall time		-	3	-	ns
<b>TR2 (P-channel), Dynamic characteristics</b>						
$Q_{G(tot)}$	total gate charge	$V_{DS} = -15\text{ V}; I_D = -410\text{ mA}; V_{GS} = -4.5\text{ V}; T_j = 25\text{ }^\circ\text{C}$	-	0.7	1.2	nC
$Q_{GS}$	gate-source charge		-	0.17	-	nC
$Q_{GD}$	gate-drain charge		-	0.16	-	nC
$C_{iss}$	input capacitance	$V_{DS} = -15\text{ V}; f = 1\text{ MHz}; V_{GS} = 0\text{ V}; T_j = 25\text{ }^\circ\text{C}$	-	43.2	-	pF
$C_{oss}$	output capacitance		-	5.9	-	pF
$C_{rss}$	reverse transfer capacitance		-	4.2	-	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = -15\text{ V}; I_D = -410\text{ mA}; V_{GS} = -4.5\text{ V}; R_{G(ext)} = 6\text{ }\Omega; T_j = 25\text{ }^\circ\text{C}$	-	3	-	ns
$t_r$	rise time		-	4	-	ns
$t_{d(off)}$	turn-off delay time		-	14	-	ns
$t_f$	fall time		-	5	-	ns
<b>TR1 (N-channel), Source-drain diode characteristics</b>						
$V_{SD}$	source-drain voltage	$I_S = 380\text{ mA}; V_{GS} = 0\text{ V}; T_j = 25\text{ }^\circ\text{C}$	-	0.86	1.2	V
<b>TR2 (P-channel), Source-drain diode characteristics</b>						
$V_{SD}$	source-drain voltage	$I_S = -410\text{ mA}; V_{GS} = 0\text{ V}; T_j = 25\text{ }^\circ\text{C}$	-	-0.95	-1.2	V

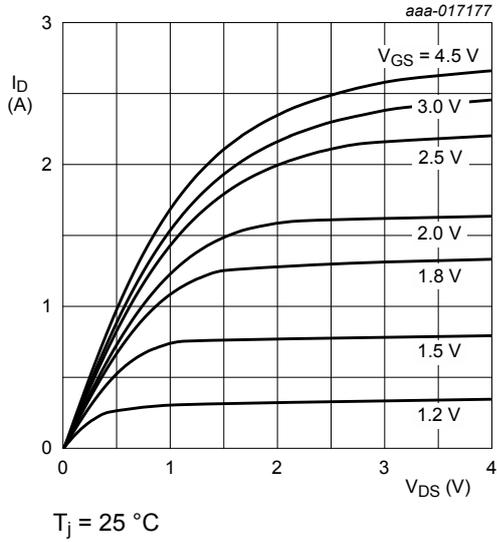


Fig. 8. TR1: Output characteristics: drain current as a function of drain-source voltage; typical values

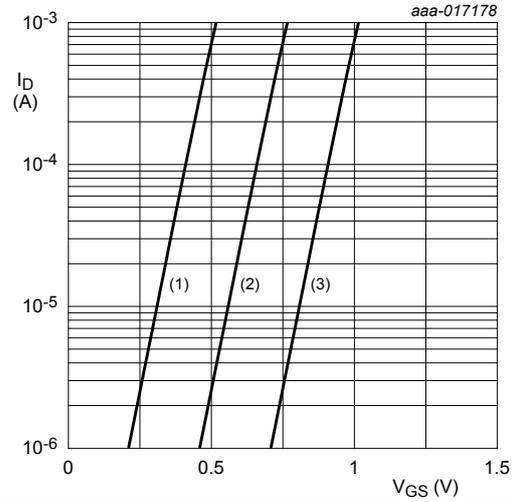


Fig. 9. TR1: Sub-threshold drain current as a function of gate-source voltage  
 (1) minimum values  
 (2) typical values  
 (3) maximum values

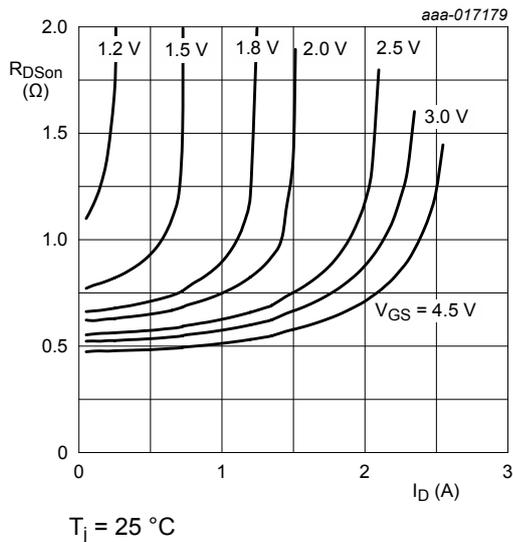


Fig. 10. TR1: Drain-source on-state resistance as a function of drain current; typical values

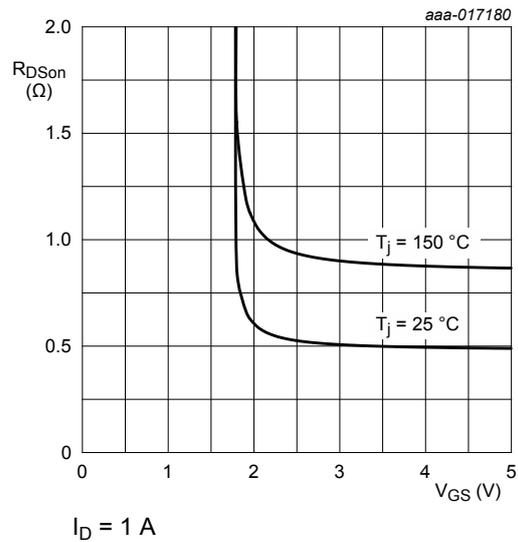
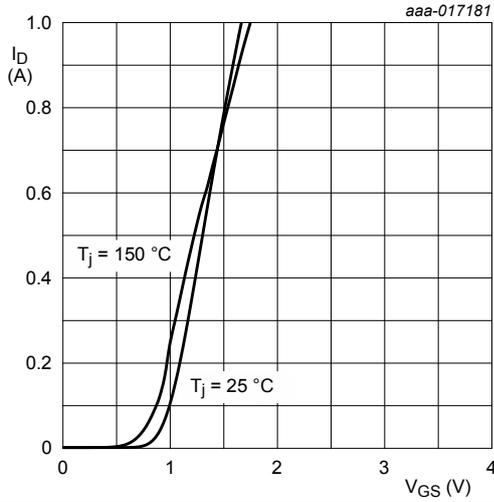
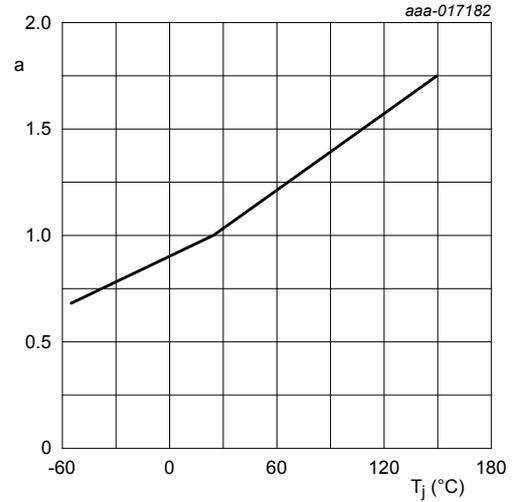


Fig. 11. TR1: Drain-source on-state resistance as a function of gate-source voltage; typical values



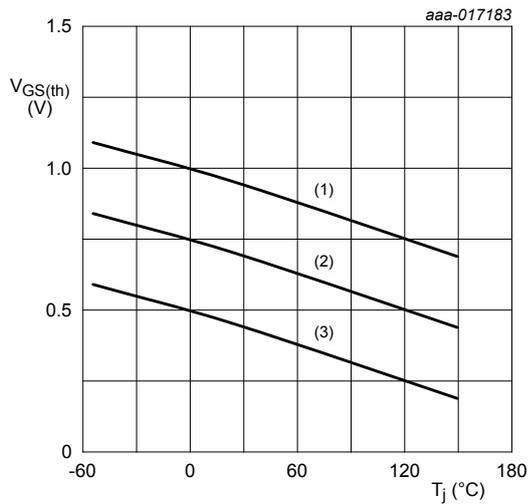
$$V_{DS} > I_D \times R_{DSon}$$

**Fig. 12. TR1: Transfer characteristics: drain current as a function of gate-source voltage; typical values**



$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

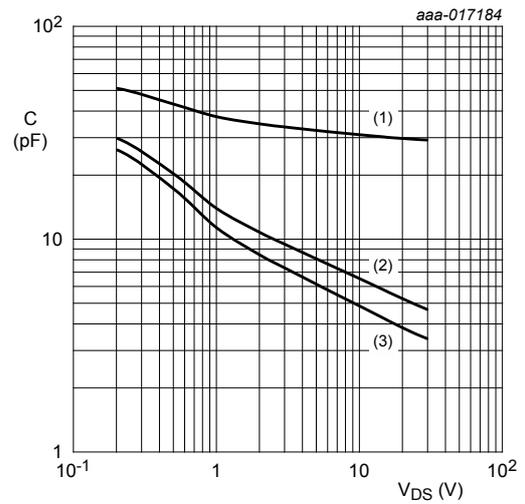
**Fig. 13. TR1: Normalized drain-source on-state resistance as a function of junction temperature; typical values**



$$I_D = 0.25 \text{ mA}; V_{DS} = V_{GS}$$

- (1) maximum values
- (2) typical values
- (3) minimum values

**Fig. 14. TR1: Gate-source threshold voltage as a function of junction temperature**



$$f = 1 \text{ MHz}; V_{GS} = 0 \text{ V}$$

- (1)  $C_{iss}$
- (2)  $C_{oss}$
- (3)  $C_{rss}$

**Fig. 15. TR1: Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values**

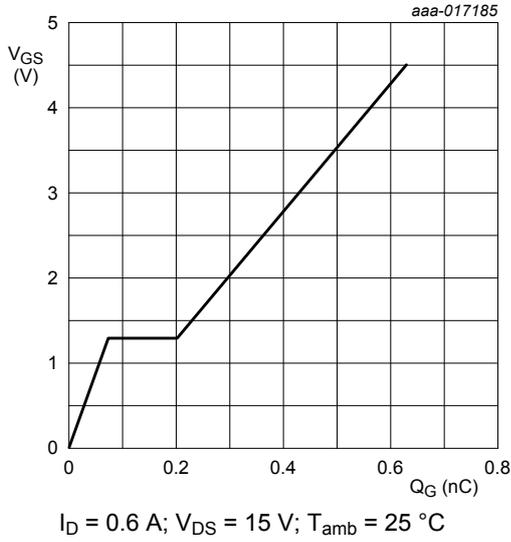


Fig. 16. TR1: Gate-source voltage as a function of gate charge; typical values

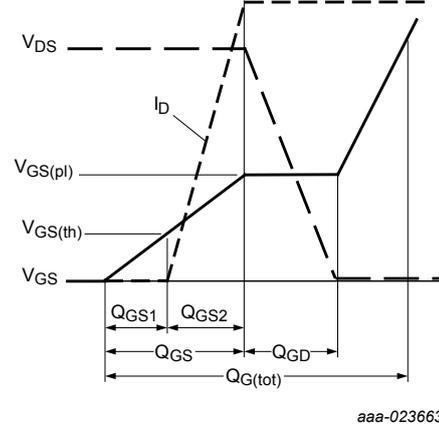


Fig. 17. TR1: Gate charge waveform definitions

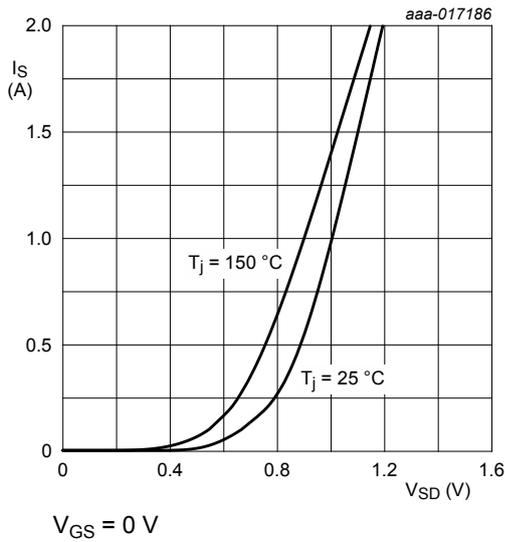


Fig. 18. TR1: Source current as a function of source-drain voltage; typical values

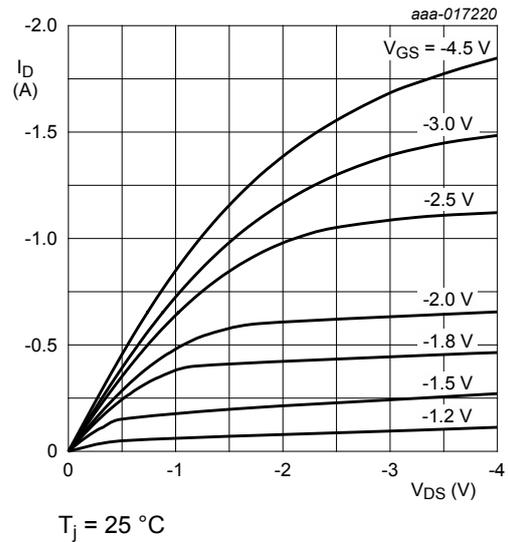
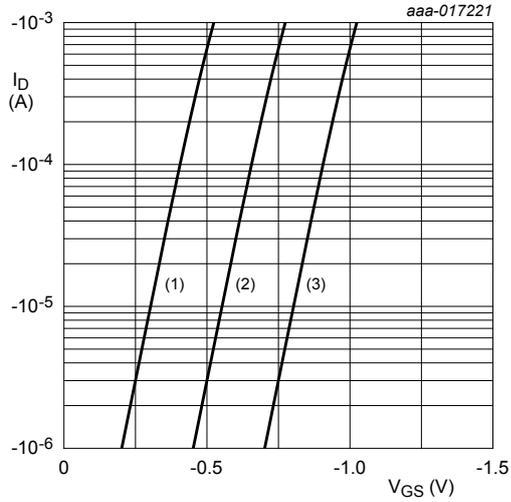
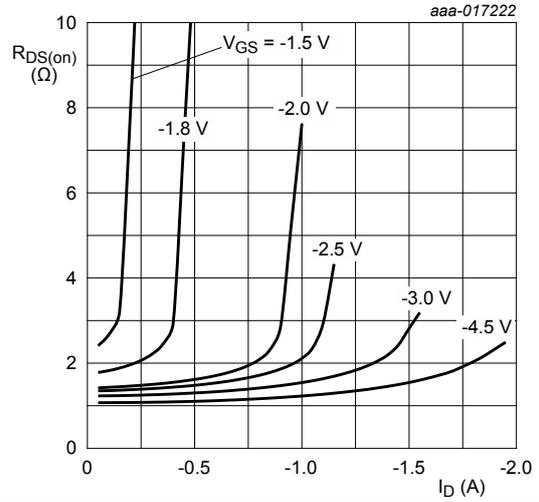


Fig. 19. TR2: Output characteristics: drain current as a function of drain-source voltage; typical values



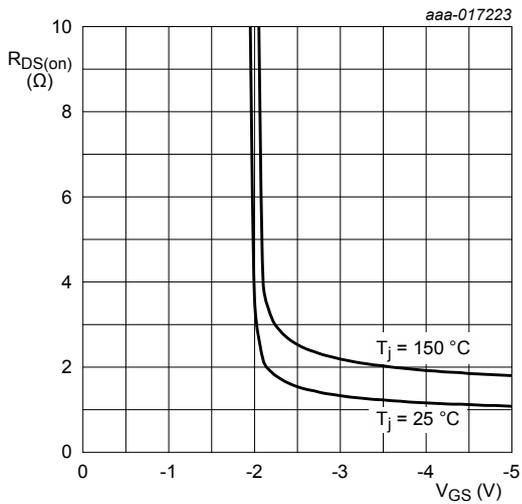
$V_{DS} = -5\text{ V}$   
 $T_j = 25\text{ }^\circ\text{C}$   
 (1) minimum values  
 (2) typical values  
 (3) maximum values

**Fig. 20. TR2: Sub-threshold drain current as a function of gate-source voltage**



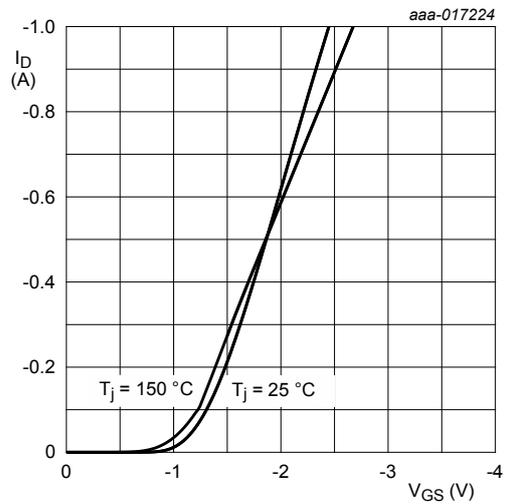
$T_j = 25\text{ }^\circ\text{C}$

**Fig. 21. TR2: Drain-source on-state resistance as a function of drain current; typical values**



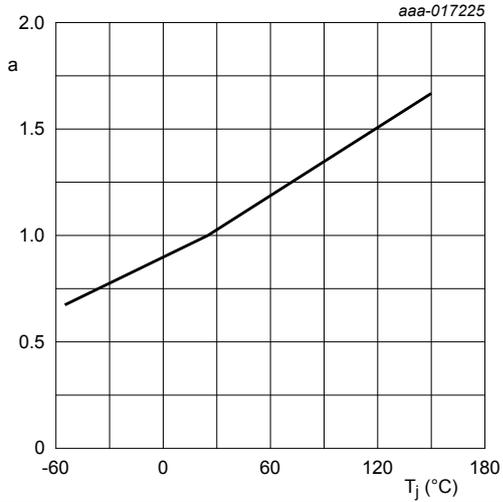
$I_D = -0.4\text{ A}$

**Fig. 22. TR2: Drain-source on-state resistance as a function of gate-source voltage; typical values**



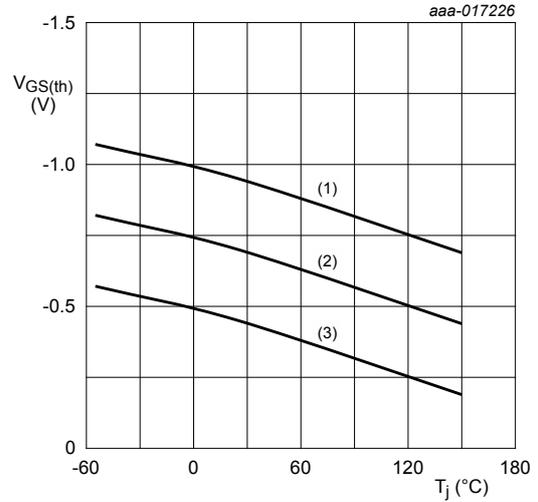
$V_{DS} > I_D \times R_{DS(on)}$

**Fig. 23. TR2: Transfer characteristics: drain current as a function of gate-source voltage; typical values**



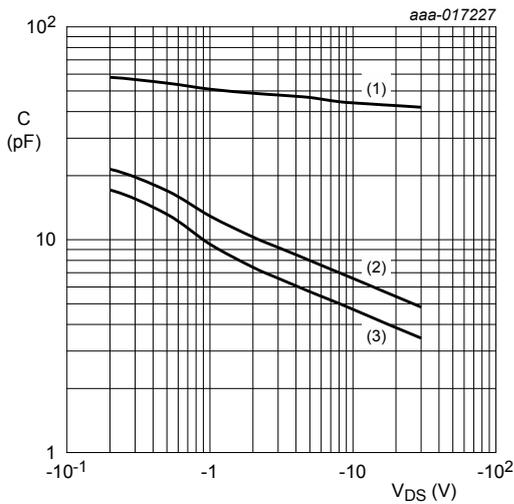
$$a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$$

**Fig. 24. TR2: Normalized drain-source on-state resistance as a function of ambient temperature; typical values**



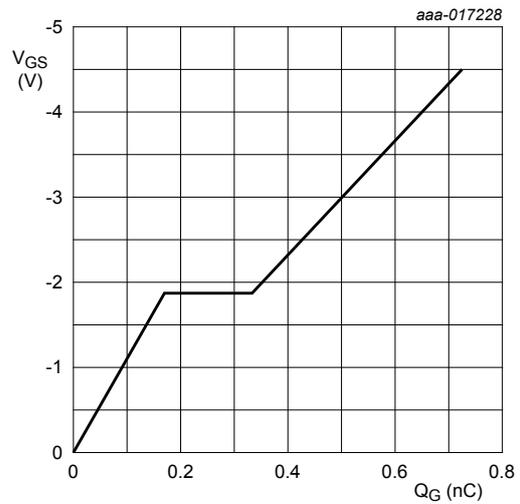
I<sub>D</sub> = -250 μA; V<sub>DS</sub> = V<sub>GS</sub>  
 (1) maximum values  
 (2) typical values  
 (3) minimum values

**Fig. 25. TR2: Gate-source threshold voltage as a function of junction temperature**



f = 1 MHz; V<sub>GS</sub> = 0 V  
 (1) C<sub>iss</sub>  
 (2) C<sub>oss</sub>  
 (3) C<sub>rss</sub>

**Fig. 26. TR2: Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values**



V<sub>DS</sub> = -15 V; I<sub>D</sub> = -410 mA T<sub>amb</sub> = 25 °C

**Fig. 27. TR2: Gate-source voltage as a function of gate charge; typical values**

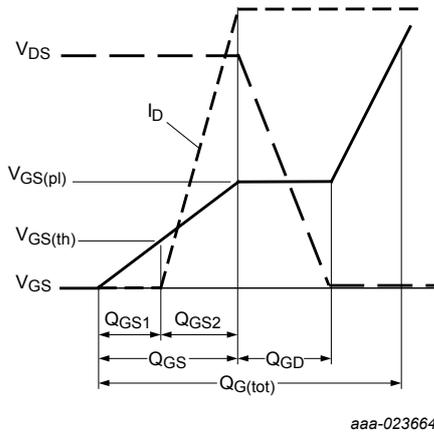


Fig. 28. TR2: Gate charge waveform definitions

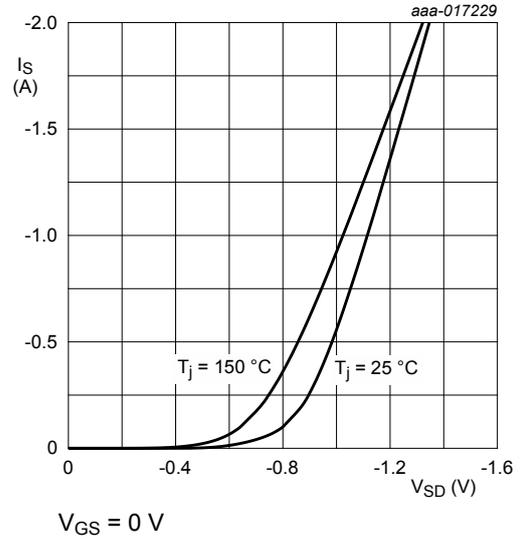


Fig. 29. TR2: Source current as a function of source-drain voltage; typical values

## 11. Test information

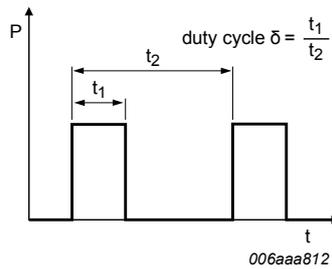


Fig. 30. Duty cycle definition

## 12. Package outline

DFN1010B-6: plastic thermal enhanced ultra thin small outline package; no leads; 6 terminals; body: 1.1 x 1.0 x 0.37 mm

SOT1216

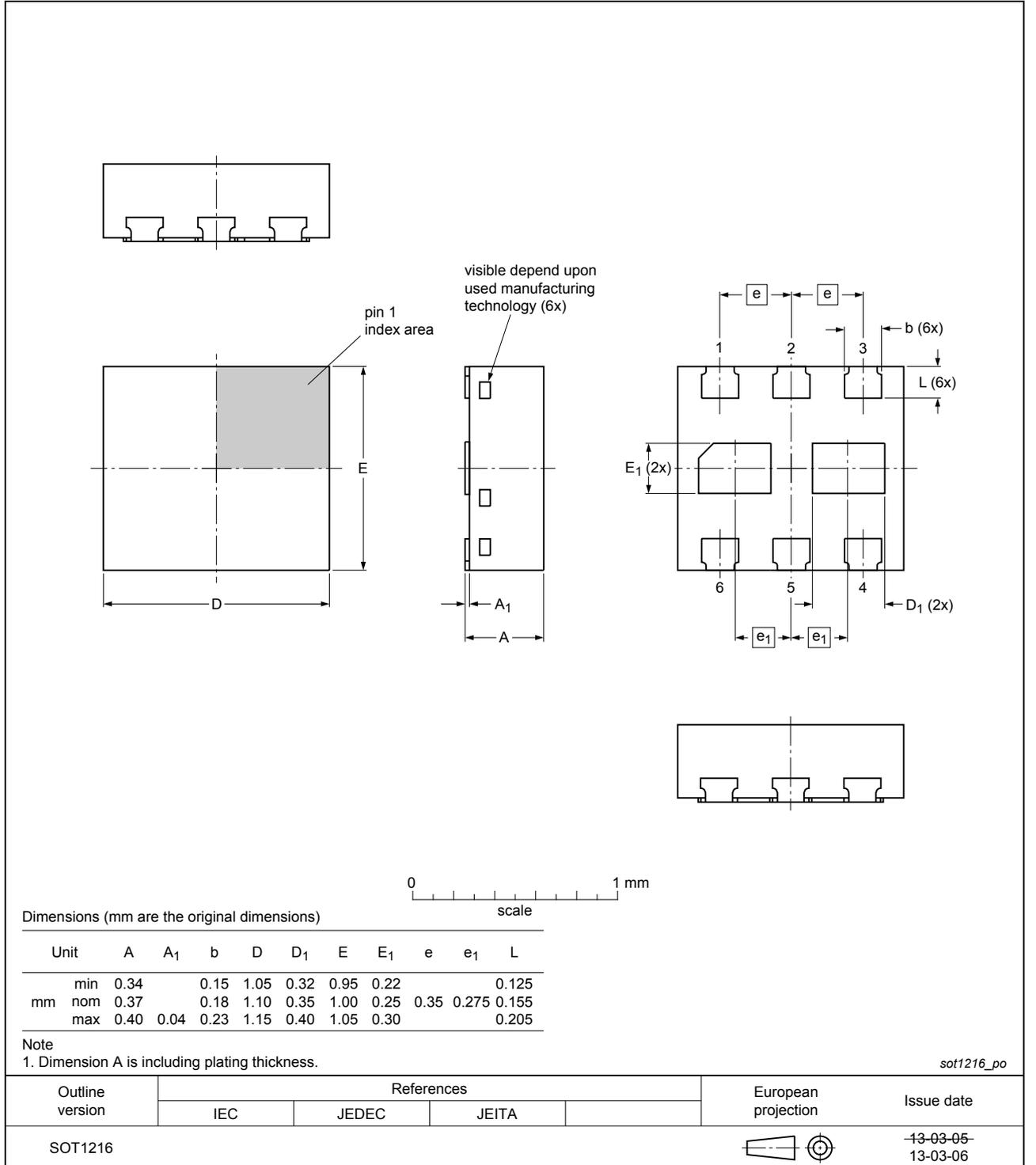
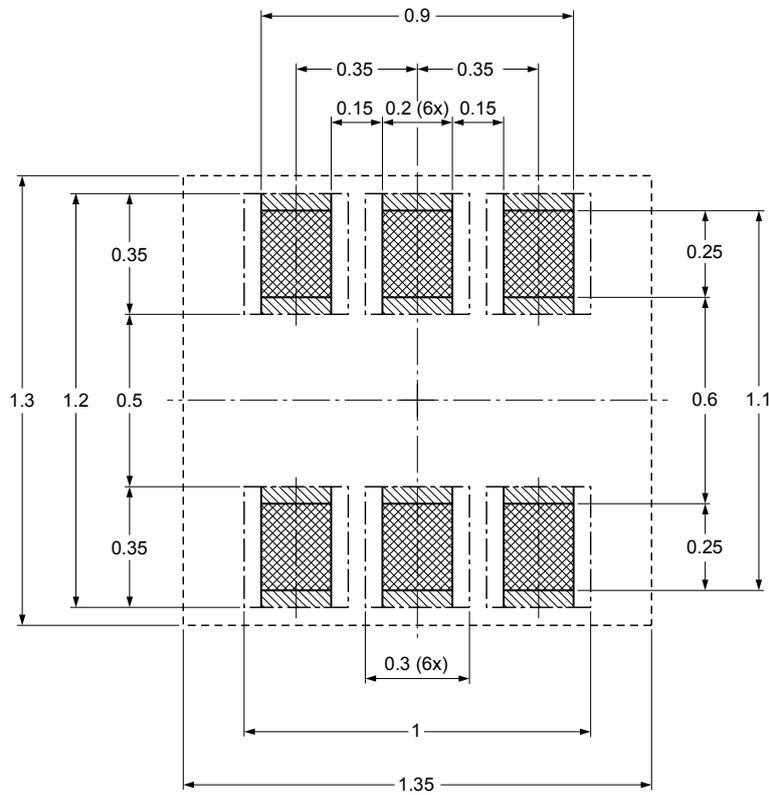


Fig. 31. Package outline DFN1010B-6 (SOT1216)

### 13. Soldering

Footprint information for reflow soldering of DFN1010B-6 package

SOT1216



-  solder land
-  solder land plus solder paste
-  occupied area
-  solder resist

Dimensions in mm

Issue date ~~13-03-06~~  
14-07-28

sot1216\_fr

Fig. 32. Reflow soldering footprint for DFN1010B-6 (SOT1216)

## 14. Revision history

Table 8. Revision history

Data sheet ID	Release date	Data sheet status	Change notice	Supersedes
PMCXB1000UE v.1	20160627	Product data sheet	-	-

## 15. Legal information

### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL <http://www.nxp.com>.

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